Author Index

Adem, E. H. 71
Anderson, P. B. 243
Angeli, J. 231

Barnegg-Golwig, G. 63
Benninghoven, A. 3
Berg, A. H. J. van den 189
Beske, H. 109
Blaufuß, K.-H. 273
Bonnenberg, D. 161
Borath, R. 137
Bouwmeester, H. J. M. 189
Bredendiek-Kämper, S. 91
Breiter, M. W. 281
Broekaert, J. A. C. 173
Brümmer, O. 35
Bubert, H. 91, 207

Čihal, V. 121

Danninger, H. 219
Dorner, G. 281
Drozak, J. 81, 91
Dudek, H. J. 137

Ebel, H. 49, 63
Ebel, M. F. 49, 63

Grasserbauer, M. 1
Gries, W. H. 55, 71
Groboth, G. 127
Grunenberg, D. 101

Hamminger, R. 195
Hanekamp, L. J. 189
Hein, M. 305
Hofer, F. 243
Hoffmann, P. 305
Holzbrecher, H. 109

Jenett, H. 91, 207

Kara, T. 219
Karduck, P. 161
Koçak, M. 251
Koch, K. H. 101
Koutník, M. 121
Krabichler, H. 259
Krismer, R. 259
Kröning, M. 25
Kruidhof, H. 189
Kudermann, G. 273

Landa, V. 121
Leucht, R. 137
Lieser, K. H. 305
Linhardt, P. 281
Lub, J. 3

Mantler, M. 63
Mayr, M. 231
Meier, B. 195

Nickel, H. 109
Nold, E. 195

Ortner, H. M. 259

Paesold, D. 231
Pimminger, M. 231
Pirš, J. 295
Pitonak, R. 243

Quadakkers, W. J. 109

Reithmayr, P. 127
Riedel, R. 207
Ruhnow, M. 219

Author Index

Adem, E. H. 71
Anderson, P. B. 243
Angeli, J. 231

Barnegg-Golwig, G. 63
Benninghoven, A. 3
Berg, A. H. J. van den 189
Beske, H. 109
Blaufuß, K.-H. 273
Bonnenberg, D. 161
Borath, R. 137
Bouwmeester, H. J. M. 189
Bredendiek-Kämper, S. 91
Breiter, M. W. 281
Broekaert, J. A. C. 173
Brümmer, O. 35
Bubert, H. 91, 207

Čihal, V. 121

Danninger, H. 219
Dorner, G. 281
Drozak, J. 81, 91
Dudek, H. J. 137

Ebel, H. 49, 63
Ebel, M. F. 49, 63

Grasserbauer, M. 1
Gries, W. H. 55, 71
Groboth, G. 127
Grunenberg, D. 101

Hamminger, R. 195
Hanekamp, L. J. 189
Hein, M. 305
Hofer, F. 243
Hoffmann, P. 305
Holzbrecher, H. 109

Jenett, H. 91, 207

Kara, T. 219
Karduck, P. 161
Koçak, M. 251
Koch, K. H. 101
Koutník, M. 121
Krabichler, H. 259
Krismer, R. 259
Kröning, M. 25
Kruidhof, H. 189
Kudermann, G. 273

Landa, V. 121
Leucht, R. 137
Lieser, K. H. 305
Linhardt, P. 281
Lub, J. 3

Mantler, M. 63
Mayr, M. 231
Meier, B. 195

Nickel, H. 109
Nold, E. 195

Ortner, H. M. 259

Paesold, D. 231
Pimminger, M. 231
Pirš, J. 295
Pitonak, R. 243

Quadakkers, W. J. 109

Reithmayr, P. 127
Riedel, R. 207
Ruhnow, M. 219

Sasse, A. G. B. M. 189
Scheuer, V. 305
Schmelzer, F. 251
Schreinlechner, I. E. 127
Schuster, H. 109
Schwarz, K. 149
Sommer, D. 101
Spiradek, K. 127
Stadelmann, H. 207
Steffan, I. 315
Steffens, H.-D. 81
Štrbački, Ž. 161
Svagera, R. 63

Thien, V. 25
Tölg, G. 173

Ullrich, H.-J. 19, 219

Velzen, P. N. T. van 3
Vetterlein, P. 25
Vujicic, G. 315

Warbichler, P. 243
Wel, H. van der 3
Werfel, F. 35
Wielage, B. 81, 91
Wilhartitz, P. 259
Winschuh, E. 25
Wyciślik, A. 287

Zalar, A. 295
Ziegler, G. 137

Subject Index

alloyed steels 219
Al_2O_3 91, 207
aluminium analysis 273
analysis 305
analysis of isolates 287
analysis without reference samples 49
analytical electron microscopy 243
analytical transmission electron microscopy (TEM) 137
angle-resolved X-ray photoelectron spectroscopy (XPS) 71
atomic absorption spectrometry (AAS) 259, 287
atomic spectrometry 173
Auger 91, 207
Auger electron spectroscopy (AES) 121, 189, 295

beta″ alumina 281

calibration standards 101
carbonaceous surface contamination 71
cast aluminium alloy 295
cemented carbides 243
ceramics 173, 189, 207
chlorine 273
coated materials 101
coating 81, 91, 243
coating thickness 231
composite powders 207
composites 81
concentration mapping 231
corrosion 127
creep 25
Cr-Ni steel 121

depth distribution 55
divergent beam X-ray diffraction 19

electron beam treatment 81
electron probe microanalysis (EPMA) 161, 231
energy dispersive X-ray/wavelength dispersive X-ray (EDX/WDX) spectrometry 295
etching 315

factor analysis 207
fatigue 25
fibre-reinforced composites 81
field metallography 25
film thickness 231
fitting 55
free cutting steels 315
fusion 127

γ' phase 287
glow discharge mass spectrometry (GDMS) 259
grain boundary 121
growth mechanism 109

high-temperature (HT) superconductors 149, 161
homogenization 219
hot isostatic pressing (HIP) 81

imaging photoelectron spectrometry 63
impurities 121, 195
inductively coupled plasma atomic emission spectrometry (ICP-AES) 259
inductively coupled plasma mass spectrometry (ICP-MS) 259
inorganic analysis 173
interface in SiC-fiber reinforced Ti6Al4V 137

ion-formation 3
ion implantation 55

Kossel technique 19

laser-aided thermal microscope 25
laser beam treatment 81
lithium 127
low energy electron diffraction (LEED) reflection 35

manufacturing 81
microanalysis 195
microprobe analysis 219
microstructure 35
mobile device 25

native oxide layer 71
neutron activation analysis (NAA) 259, 281
NiCrAl 91

offshore steels 251
organic surface analysis 3
overlayer thickness 63
oxide-dispersion strengthened (ODS) alloys 109
oxide scales 109
oxygen-tracer 109
oxygen value 251

phase analysis 161
phosphorus 273
photoelectron spectroscopy 35
photothermal effect 25
pixel analysis 63
plasma-spraying 91
post treatment 81
properties at and below materials surfaces 25
properties of thermal waves 25

quantification 3, 101
quantitative microanalysis of oxygen 161
quantitative surface analysis 49, 63, 101

secondary ion mass spectrometry (SIMS) 109, 259
secondary neutral mass spectrometry (SNMS) 101, 251
segregation 121
selected area analysis 63
shot peening 81
SiC-platelets 195
silicon wafer 71
Si_3N_4 207
Si_2N_2O 207
sintering 219
small spot analysis 63
solid electrolyte 281
solid state mass spectrometry 259
spark ablation 315
spark ablation and inductively coupled plasma (spark-ICP) 315
spark source mass spectrometry (SSMS) 259
spin-polarization 35
split Student-*t* functions 55
sputtering 189
St 37 91
stainless steel 127
static secondary ion mass spectrometry 3
sulfur 273

thermal spraying 81
thermal stability 137
thickness distribution mapping 231
thin films 305
time-of-flight 3
total reflection 305
toughness 251
trace-matrix separation 259
transient liquid phase 219
transmission electron microscopy (TEM) preparation 137

welds 251

X-ray excited Auger electron spectroscopy 49
X-ray fluorescence 305
X-ray photoelectron spectroscopy (XPS) 49, 189

ZrO_2-7.25Y_2O_3 91